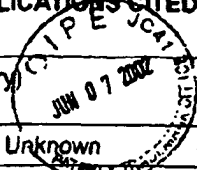


U.S. Department of Commerce, Patent and Trademark Office				Docket No. 8033064		Serial No. 10/000,001	
(PTO Form 1449 modified)							
<b>LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT</b>				Applicant Wang et al.			
(Use several sheets if necessary)				Filing Date October 24, 2001		Group 2877	
Examiner <u>Unknown</u>				<div style="border: 1px solid black; padding: 2px; display: inline-block;">             COPY OF PAPERS ORIGINAL FILED ORIGINAL FILE           </div>			



U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
PJL	1	5,999,261	12/7/99	Pressesky et al.	<del>256</del>	<del>054</del>	7/10/98
	2						
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Foreign Patent Documents								
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	14						<input type="checkbox"/>	<input type="checkbox"/>
	15						<input type="checkbox"/>	<input type="checkbox"/>
	16						<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART		
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
PJL	17	Chris L. Koliopoulos, "Simultaneous phase shift interferometer", Advanced Optical Manufacturing and Testing II, Proc. SPIE Vol. 1531, p. 119-127 (1991).
PJL	18	Jianmin Wang and Ian Grant, "ESPI, Phase mapping, NDT the techniques applied to real-time, thermal loading", Appl. Opt. 34, 3620-3627
	19	

Examiner <u>PATRICK CONNELLY</u>	Date Considered <u>9.30.2003</u>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.